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☐ 1. Document ID: US 6877343 B2

AB: In a magnetic recording medium, surface roughness of a glass substrate and the variation of the surface roughness are suppressed to the predetermined range. Namely, the surface roughness (Rmax, Ra, Rq) and the relation (Rmax/Ra) between Rmax and Ra are restricted to the predetermined range. In this event, Ra is representative of a center-line mean roughness, Rmax is defined as a maximum height representative of a difference between a highest point and a lowest point and Rq is representative of a root mean square roughness. Thereby, crystal grains of an underlying layer and a magnetic layer formed thereon are equalized. Specifically, the surface roughness is specified by Rmax.ltoreq.15 nm, Ra.ltoreq.1 nm and Rq.ltoreq.1.5 nm. Further, the ratio between the surface roughness Rmax and the surface roughness Ra is specified by Rmax/Ra.ltoreq.30.

Full | Title | Citation | Front | Review | Classification | Date | Reference | Claims | KWIC | Draw Des

☐ 2. Document ID: US 6790509 B2

AB: A substrate for an information recording medium, wherein the period of microwaviness is 2 .mu.m to 4 mm, and if we let wa be the maximum height of this microwaviness and Rmax be the maximum height measured by atomic force microscope, the main surface of the substrate has a wa of no more than 5 nm and an Rmax of no more than 12 nm, provided that wa is the difference between the highest and lowest points on a measurement curve of all measured points in a measurement area.

Full | Title | Citation | Front | Review | Classification | Date | Reference | Claims | KWIC | Draw Des

☐ 3. Document ID: US 6782717 B2

AB: A method for manufacturing a disk-like glass substrate that is used as an information recording medium. The glass substrate is acid resistant. When an index of acid resistance is the maximum depth at which components other than silica dissolve from the glass substrate during immersion of the glass substrate in 1 percentage of weight of sulfuric acid, the acid resistance of the glass substrate is represented by the maximum depth of 0.5 nm to 10 nm. A linear texture is formed by pressing a tape against the glass substrate in a circumferential direction of the

glass substrate while feeding abrasion slurry to the surface of the glass substrate. Acid treatment is performed on the glass substrate on which the texture is formed.

Full | Title | Citation | Front | Review | Classification | Date | Reference | Claims | KWIC | Draw Des

4. Document ID: US 6706427 B2

AB: There are disclosed an information recording medium substrate having a surface roughness of Rmax 15 nm or less, and an information recording medium, particularly an information recording medium substrate and information recording medium in which for surfaces of the substrate and medium, a bearing area value (offset bearing area value) in a depth of 0.5 to 5 nm (predetermined slice level) from a bearing height (real peak height) corresponding to the bearing area value of 0.2% to 1.0% is 90% or less, and a manufacture method of the substrate and medium.

Full | Title | Citation | Front | Review | Classification | Date | Reference | Claims | KWIC | Draw Des

5. Document ID: US 6277465 B1

AB: In a magnetic recording medium, surface roughness of a glass substrate and the variation of the surface roughness are suppressed. Namely, the surface roughness (Rmax, Ra, Rq) and the relation (Rmax/Ra) between Rmax and Ra are restricted. Ra is representative of a center-line mean roughness, Rmax is defined as a maximum height representative of a difference between a highest point and a lowest point and Rq is representative of a root mean square roughness. Thereby, crystal grains of an underlying layer and a magnetic layer formed thereon are equalized. The surface roughness is specified by Rmax.ltoreq.15 nm, Ra.ltoreq.1 nm and Rq.ltoreq.1.5 nm and the ratio between the surface roughness Rmax and the surface roughness Ra is in the range of 10 to 30.

Full | Title | Citation | Front | Review | Classification | Date | Reference | Claims | KWIC | Draw Des

6. Document ID: US 6187441 B1

AB: A glass substrate contains at least ZrO.sub.2 and Li.sub.2 O. In this event, ZrO.sub.2 has a content which falls within the range between 0.6 and 1.9 mol % while Li.sub.2 O has a content which falls within the range between 6 and 14 mol %. Thus, the contents of ZrO.sub.2 and Li.sub.2 O are restricted to a predetermined range. Consequently, the projections of the undissolved substance of ZrO.sub.2 are not formed on the surface of the glass substrate. As a result, the glass substrate having the flat surface can be obtained.